Notice of References Cited	Application/Control No. 10/566,988	Applicant(s)/Pater Reexamination MIURA ET AL.		
	Examiner	Art Unit	Page 1 of 1	
	Seung H. Lee	2887		
U.S. PATENT DOCUMENTS				

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,173,900	01-2001	Yoshigi et al.	235/492
	В	US-			
	U	US-			
	ם	US-			
	Е	US-			
	F	US-			
	O	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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